

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	11	semiconductor and ((roll\$4 or fold\$4) adj tape) and adhesive and (chip or die) and ball and stack and @ad<="20021230"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/26 10:19
L2	38	438/107,109,110,112,124,126,127,612,618,617,666.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature) and (c4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/26 10:19
L3	0	(semiconductor and ((roll\$4 or fold\$4) adj tape) and adhesive and (chip or die) and ball and stack).clm.	US-PGPUB	OR	ON	2006/05/26 10:19
S1	1	("20040180471").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/21 14:40
S2	993	(438/107).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/12/14 09:17
S3	598	(438/109).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/12/14 09:33
S4	469	(438/112).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/24 12:41
S5	767	(438/124).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/24 12:41

## EAST Search History

S6	750	(438/126).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/24 12:41
S7	1104	(438/127).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/24 12:41
S8	973	(438/618).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/24 12:41
S9	556	(438/666).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/24 12:41
S10	321	(438/617).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/24 12:42
S11	342	(438/110).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/27 12:30
S12	13	semiconductor same stack\$5 same lead same (flux or reflow or encapsul\$6) same solder same ((heat adj treat\$6) or temperature)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/27 09:59
S13	2	semiconductor with stack\$5 with lead with (flux or reflow or encapsul\$6) with solder with ((heat adj treat\$6) or temperature)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/27 08:15

## EAST Search History

S16	2528	semiconductor and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/27 11:47
S17	343	438/107,109,110,112,124,126,127,612,618,617,666.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/14 08:39
S18	422	257/685,686,784,786,773,777,723.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/27 12:57
S19	1	("20040157374").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/26 12:33
S20	2	("6656840").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/27 09:48
S22	47	(anisotropic adj conduct\$5 adj adhesive) same (chip or die or ((integrated adj circuit) or ("IC"))) same (solder adj ball)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/27 06:42
S23	5	(anisotropic adj conduct\$5 adj adhesive) with fold\$6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/27 06:44
S24	14	(anisotropic adj conduct\$5 adj adhesive) same fold\$6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/23 10:48
S26	1	("6790710").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/27 10:10

## EAST Search History

S30	5	((("5523605") or ("20040152290") or ("6683350"))).PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/27 12:37
S36	2	((("6836006") or ("20020043708"))).PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/11/28 14:17
S38	7	(anisotropic adj conduct\$5 adj adhesive) with (semiconductor adj packag\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/23 10:49
S39	1068	(438/107).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/12/23 10:50
S40	71	438/107,109,110,112,124,126,127,612,618,617,666.ccls. and (anisotropic adj conduct\$5 adj adhesive)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/23 10:52
S42	5	((("6300679") or ("6737300") or ("6635968") or ("6620652") or ("6582992"))).PN.	USPAT	OR	OFF	2004/12/27 09:48
S43	2	438/107,109,110,112,124,126,127,612,618,617,666.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature) and ("c.sub.4")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 12:07
S44	6	"438"/\$.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature) and ("c.sub.4")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 12:05
S45	93	"438"/\$.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature) and ("c4")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 12:06

## EAST Search History

S46	0	("438"/\$.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature)) with ("c4")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 12:06
S47	0	("438"/\$.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature)) same ("c4")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 12:06
S48	0	("438"/\$.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature)) same c4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 12:06
S49	0	("438"/\$.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature)) with c4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 12:07
S50	93	("438"/\$.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature)) and c4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 12:09
S51	199	("257"/\$.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature)) and c4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 12:07
S52	30	438/107,109,110,112,124,126,127,612,618,617,666.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature) and (c4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/14 09:34
S53	2	438/107,109,110,112,124,126,127,612,618,617,666.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature) and (c4 adj (process or method))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 12:09
S54	8	("438"/\$.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature)) and (c4 adj (process or method))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 12:21

## EAST Search History

S55	15	("257"/\$.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature)) and (c4 adj (process or method))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/31 12:21
S56	11	("257"/\$.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature)) and (c4 adj (process or method))	USPAT	OR	ON	2005/05/31 12:21
S57	6	("438"/\$.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature)) and (c4 adj (process or method))	USPAT	OR	ON	2005/12/14 09:34
S58	1	("6765288").PN.	USPAT	OR	OFF	2005/11/28 14:17
S59	324	438/118,464,119,107,109,110,112,124,126,127,612,618,617,666.ccls. and tape and (chip or die) and ball and stack	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/14 08:43
S60	196	438/118,464,119,107,109,110,112,124,126,127,612,618,617,666.ccls. and tape and (chip or die) and ball and stack and @ad<="20021230"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/14 09:09
S61	7	"438"/\$.ccls. and ((roll\$4 or fold\$4) adj tape) and adhesive and (chip or die) and ball and stack and @ad<="20021230"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/14 09:10
S62	13	"257"/\$.ccls. and ((roll\$4 or fold\$4) adj tape) and adhesive and (chip or die) and ball and stack and @ad<="20021230"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/14 09:13
S63	11	semiconductor and ((roll\$4 or fold\$4) adj tape) and adhesive and (chip or die) and ball and stack and @ad<="20021230"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/26 10:18
S64	0	(semiconductor and ((roll\$4 or fold\$4) adj tape) and adhesive and (chip or die) and ball and stack).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/12/14 09:16

## EAST Search History

S65	0	(semiconductor and ((roll\$4 or fold\$4) adj tape) and adhesive and (chip or die) and ball and stack).clm.	US-PGPUB	OR	ON	2006/05/26 10:19
S66	1240	(438/107).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/12/14 09:24
S67	1497	(438/118).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/12/14 09:29
S68	366	(438/119).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/12/14 09:29
S69	844	(438/109).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/12/14 09:33
S70	34	438/107,109,110,112,124,126,127,612,618,617,666.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature) and (c4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/26 10:19
S71	6	("438"/\$.ccls. and stack\$5 and lead and (flux or reflow or encapsul\$6) and solder and ((heat adj treat\$6) or temperature)) and (c4 adj (process or method))	USPAT	OR	ON	2005/12/14 09:34